

Search Notes

Application/Control No.

10/682,153

Examiner

Hien N. Nguyen

Applicant(s)/Patent under
Reexamination

TANAKA, SHINJI

Art Unit

2824

SEARCHED

Class	Subclass	Date	Examiner
365	189.01	4/28/2005	HNN
	189.05		
	189.08		
	230.06		
	230.08		
	233		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
365	230.06	5/12/2005	HN
	233		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	4/28/2005	HN